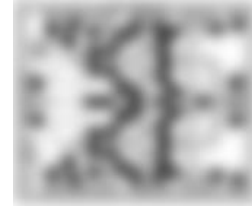


Product Description

The Nxbeam NPA2020-DE is a K-band high power amplifier MMIC fabricated in 0.2um GaN HEMT on SiC. This part is ideally suited for satellite communication, mobile communication, and radar applications. The MMIC operates from 23 to 25 GHz and provides an average of 8 W of saturated output power, 33% PAE, and a linear gain of 17 dB.



The NPA2020-DE comes in die form with RF input and output matched to 50 Ω with DC blocking capacitors for easy system integration. The HEMT devices are fully passivated for reliable operation. Bond pad and backside metallization are Au-based for compatibility with eutectic die attachment methods.

Key Features

- Frequency: 23 – 25 GHz
- Linear Gain (Ave.): 17 dB
- Psat (Ave.): 8 W
- PAE (Ave.): 33 % (36% at 20V)
- Chip Dimensions: 2.5 x 2.0 x 0.1 mm

Electrical Specifications

Test Condition: Vd = 24 V (unless otherwise noted), Idq = 140 mA, Pulsed On-Wafer Data, Typical Performance at 25°C

| Parameter | | Min | Typical | Max | Unit |
|--------------------------------------|--------|-----|---------|-----|------|
| Frequency | | 23 | | 25 | GHz |
| Gain (Small Signal Average) | | | 17 | | dB |
| Output Power (Average at Pin=24 dBm) | 24 V | | 39 | | dBm |
| | 20 V | | 38.2 | | |
| PAE (Average at Pin=24 dBm) | 24 V | | 33 | | % |
| | 20 V | | 36 | | |
| Power Gain (Average at Pin=24 dBm) | 24 V | | 15 | | dB |
| | 20 V | | 14.2 | | |
| Input Return Loss | 23 GHz | | 8 | | dB |
| | 24 GHz | | 25 | | |
| | 25 GHz | | 4 | | |
| Output Return Loss | 23 GHz | | 25 | | dB |
| | 24 GHz | | 13 | | |
| | 25 GHz | | 16 | | |

Absolute Maximum Ratings (Temp. = 25°C)

| Parameter | Min | Max | Unit |
|-----------------------------------|-----|------|------|
| Drain Voltage (Vd1, Vd2) | | 28 | V |
| Drain Current (Id1) | | 380 | mA |
| Drain Current (Id2) | | 1000 | mA |
| Gate Voltage (Vg1, Vg2) | -7 | 0 | V |
| Input Power (Pin) | | TBD | dBm |
| Assembly Temperature (30 seconds) | | 320 | °C |

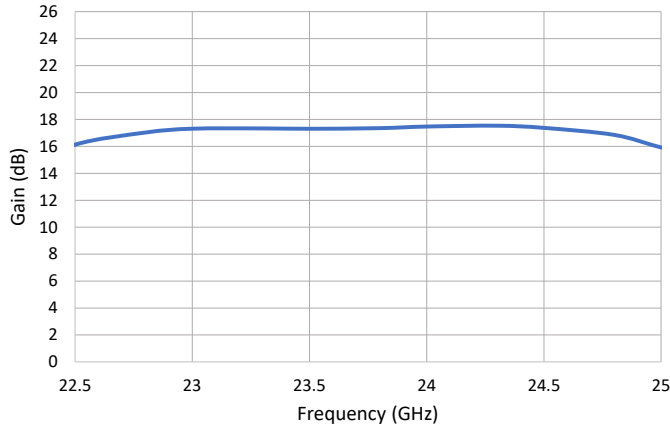
Recommended Operating Condition

| Parameter | Value | Unit |
|-----------------------------|-----------|------|
| Drain Voltage (Vd) | 20 - 28 | V |
| Drain Current (Idq) | up to 550 | mA |
| Gate Voltage (Vg) (Typical) | -3.8 | V |

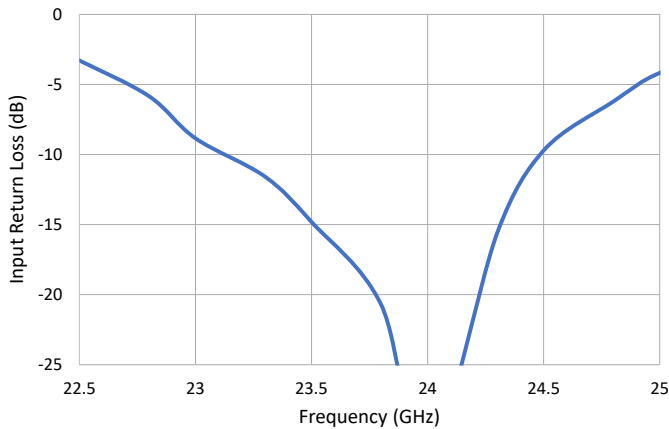
Small Signal Performance

Test Condition: $V_d = 24\text{ V}$, $I_{dq} = 140\text{ mA}$, (Pulsed On-Wafer Data, Typical Performance at 25°C)

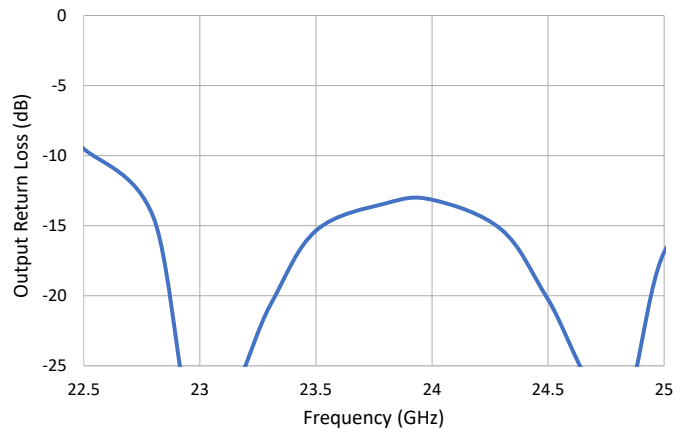
Gain vs. Frequency



Input Return Loss vs. Frequency

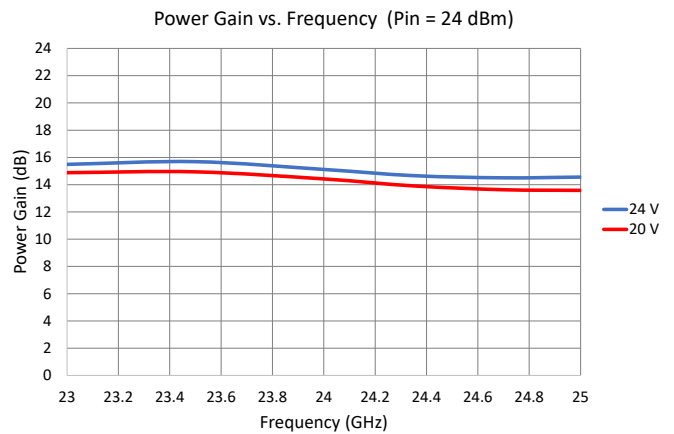
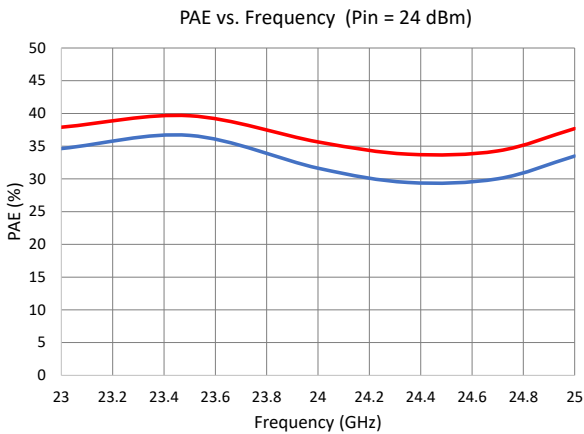
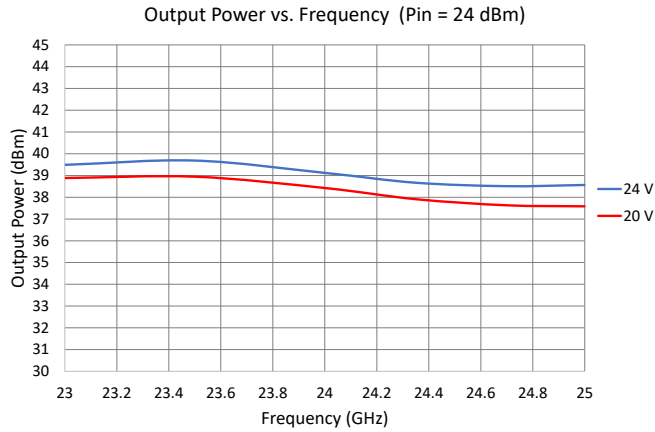


Output Return Loss vs. Frequency



Large Signal Performance

Test Condition: $V_d = 20 \text{ \& } 24 \text{ V}$, $I_{dq} = 140 \text{ mA}$, $P_{in} = 24 \text{ dBm}$
(Pulsed-Power On-Wafer Data, Typical Performance at 25°C)

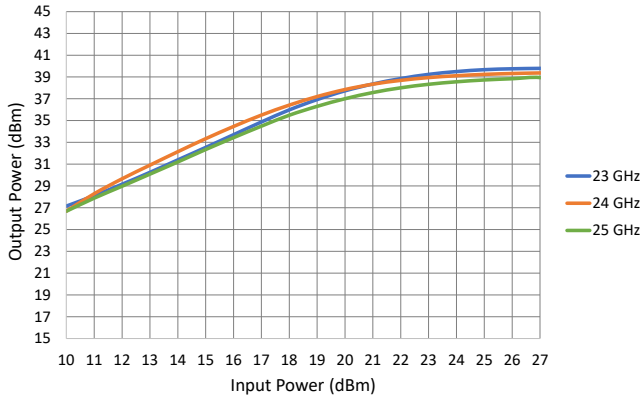


Large Signal Performance

(Pulsed-Power On-Wafer Data, Typical Performance at 25°C)

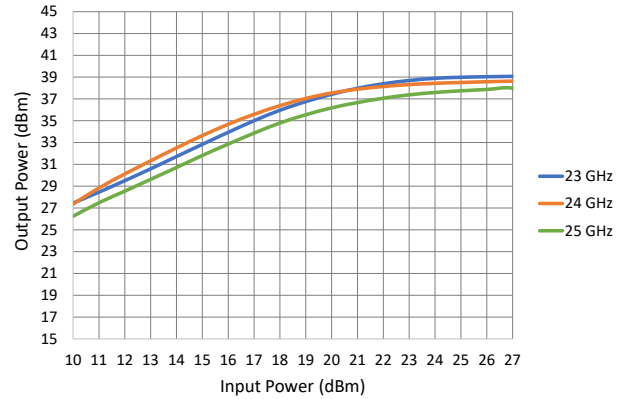
Test Condition: $V_d = 24\text{ V}$, $I_{dq} = 140\text{ mA}$

Output Power vs. Input Power vs. Frequency

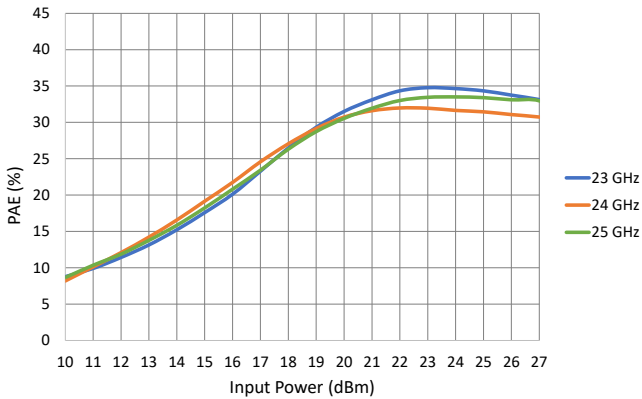


Test Condition: $V_d = 20\text{ V}$, $I_{dq} = 140\text{ mA}$

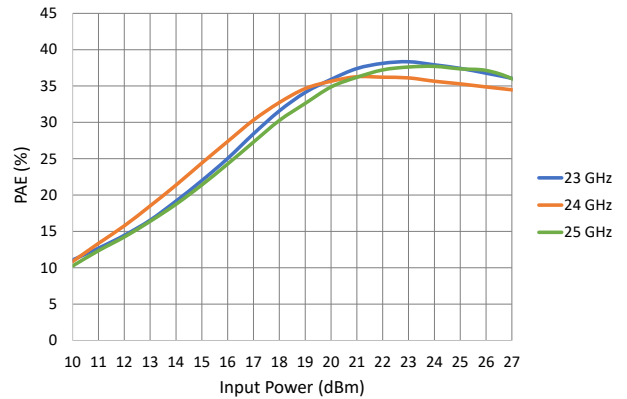
Output Power vs. Input Power vs. Frequency



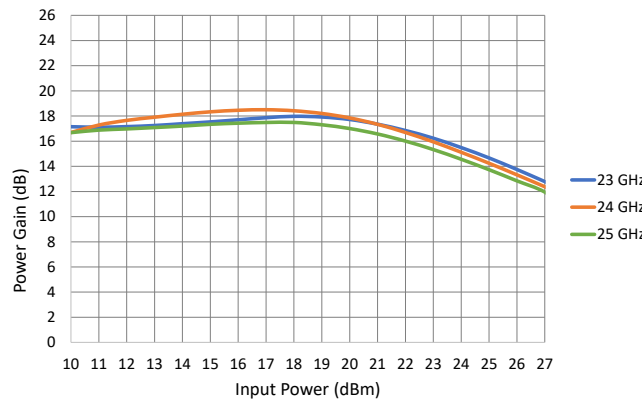
PAE vs. Input Power vs. Frequency



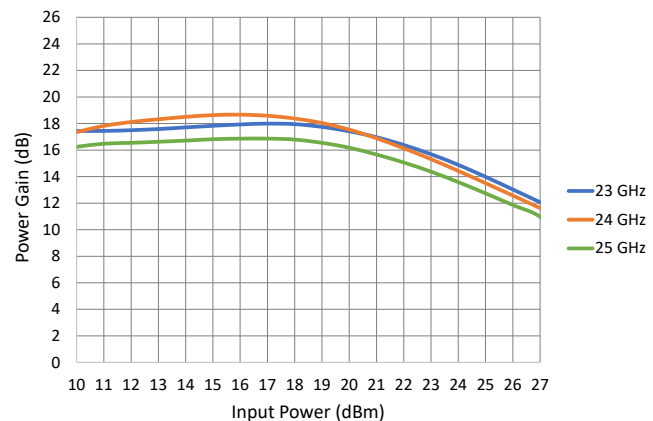
PAE vs. Input Power vs. Frequency



Power Gain vs. Input Power vs. Frequency



Power Gain vs. Input Power vs. Frequency



Thermal Information

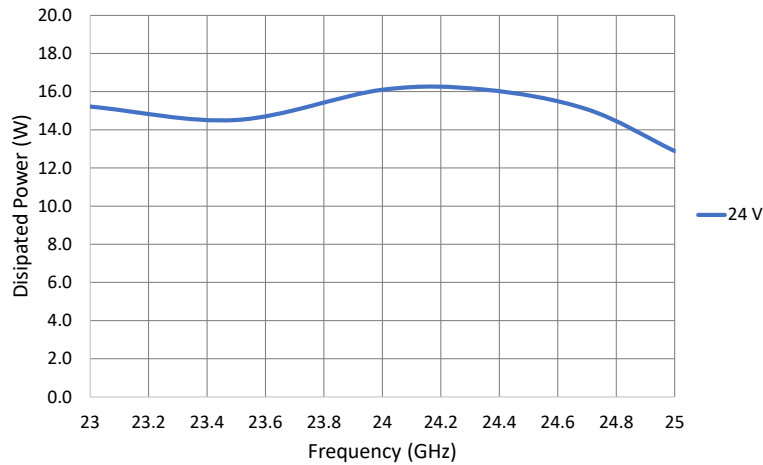
RF = Off

| Parameter | Condition | Value | Unit |
|--|--|-------|------|
| Thermal Resistance ($R_{\theta JC}$) | RF=OFF | 5.5 | °C/W |
| Junction Temperature (T_j) | $T_{backside}=85\text{ °C}$, $V_d=24\text{ V}$, $I_{dq}=0.14\text{ A}$, $P_{dis}=3.36\text{ W}$ | 103.5 | °C |

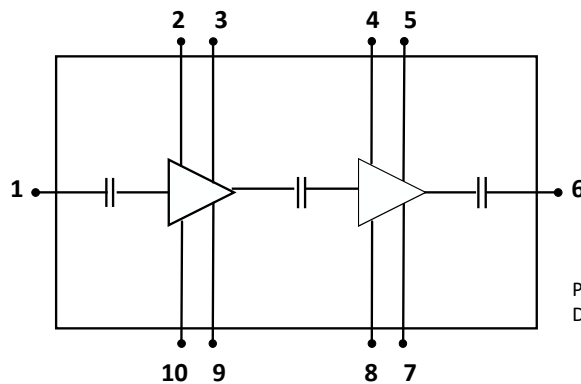
RF = On, Peak Junction Temperature at Pin = 21 dBm, Psat

| Parameter | Condition | Value | Unit |
|--|---|-------|------|
| Thermal Resistance ($R_{\theta JC}$) | $P_{in}=24\text{ dBm}$, Freq.=24 GHz | 5.7 | °C/W |
| Junction Temperature (T_j) | $T_{backside}=85\text{ °C}$, $V_d=24\text{ V}$, $I_d=1.04\text{ A}$, $P_{dis}=16.1\text{ W}$ | 176.5 | °C |

Disipated Power vs. Frequency (Pin = 24 dBm)



Circuit Block Diagram



Die Size and Bond Pad Information

Chip Size = 2500 ±25 μm x 2050 ±25 μm

Chip Thickness = 100 μm

Chip Backside metal is ground

RF Input/Output Pad Dimensions = 134 μm x 208 μm

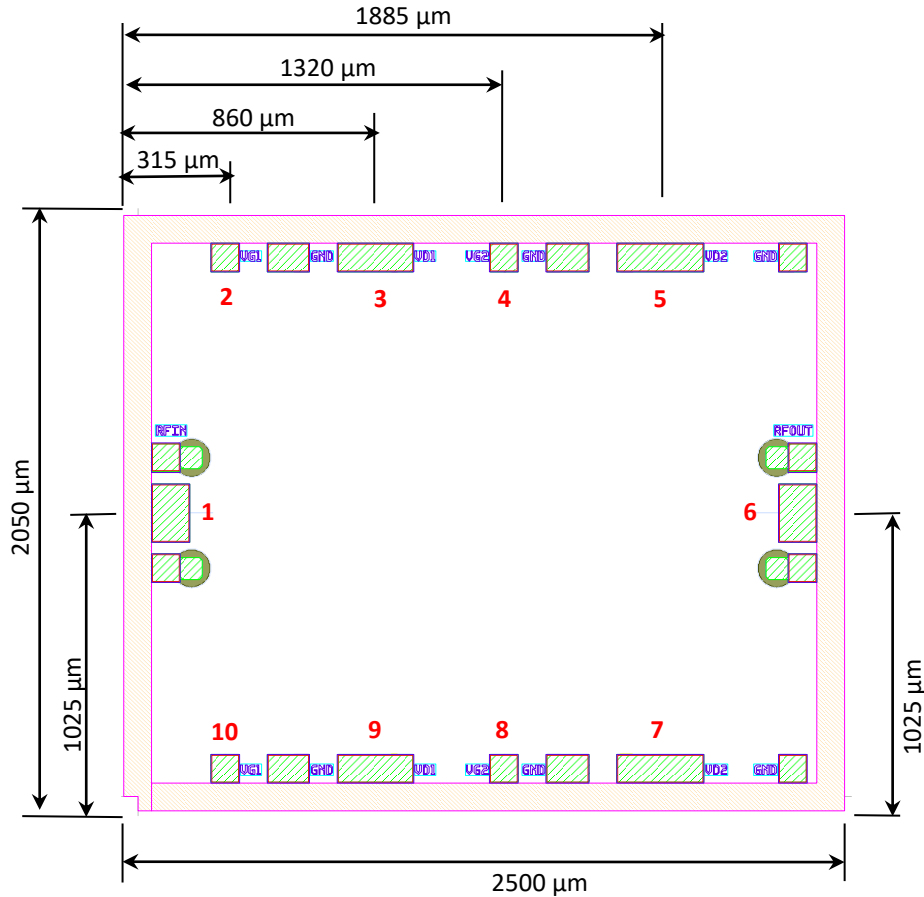
DC Pad Dimensions:

Vg1, Vg2 = 100 μm x 100 μm

Vd1 = 275 μm x 100 μm

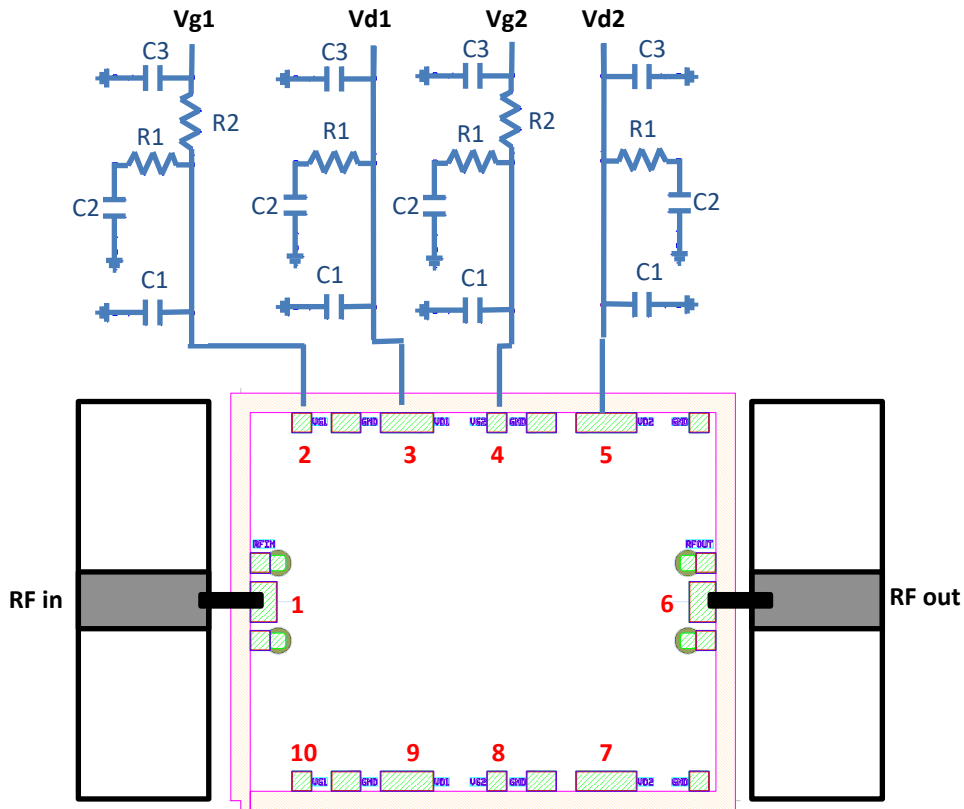
Vd2 = 315 μm x 100 μm

| Pad Num. | Function |
|----------|----------|
| 1 | RF in |
| 2, 10 | Vg1 |
| 3, 9 | Vd1 |
| 4, 8 | Vg2 |
| 5, 7 | Vd2 |
| 6 | RF out |



Suggested Off-Chip Components

The following diagram is a suggested bonding arrangement with off-chip components. It is also possible to tie all gate voltages together as well as all drain voltages together. Bias can be applied one side of the chip or both sides.



Off-Chip Component Values

| Capacitor | Value |
|-----------|--------------|
| C1 | 100 pF |
| C2 | 0.01 μ F |
| C3 | 1 μ F |

| Resistor | Value |
|----------|--------------|
| R1 | 10 Ω |
| R2 | 100 Ω |

Assembly Process

- This product has gold backside metallization and can be mounted using either a conductive epoxy or AuSn attachment.
- Nxbeam recommends the use of AuSn attachment due to the high-power level of this product.
- Maximum recommended temperature during die attachment is 320 °C for 30 seconds.
- This product contains metal air bridges so caution should be taken when handling the die to avoid damage.

Bias Information

The NPA2020-DE can be biased from either top or bottom of the chip or both sides.

Bias-up Procedure:

- 1.) It is recommended that voltage and current limits are set on the voltage supply's prior to biasing the product.
- 2.) Ensure power supplies are properly grounded to the product test fixture.
- 3.) Apply negative gate voltage (-6 V) to ensure all devices are pinched off.
- 4.) Gradually increase the drain bias voltage to the desired bias level but not to exceed the maximum voltage of 28 V.
- 5.) Gradually increase the gate voltage while monitoring the drain current until the desired drain current is achieved.
- 6.) Apply RF signal.

Bias-down Procedure:

- 1.) Turn off RF signal.
- 2.) Gradually decrease the gate voltage down to -6 V.
- 3.) Gradually decrease the drain voltage down to 0 V.
- 4.) Gradually increase gate voltage to 0 V.
- 5.) Turn off supply voltages

ESD Sensitive Product



Important Information

The data contained in this document is based on pulsed on-wafer measurements. Nxbeam Inc. reserves the right to update and change without notice the characteristic data and other specifications as they apply to this document. Customers should obtain and verify the most recent product information before placing orders. Nxbeam Inc. assumes no responsibility or liability whatsoever for the use of the information contained herein.

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